

Search Notes

Application/Control No.

10/066,188

Examiner

Sun J. Lin

Applicant(s)/Patent under
Reexamination

TEIG ET AL.

Art Unit

2825

SEARCHED

| Class | Subclass | Date | Examiner |
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| 716 | 12 | 8/15/2005 | JSL |
| 716 | 14 | 8/15/2005 | JSL |
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INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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| EAST [USPAT;US- PGPUB;EPO;JPO;DERWENT;IBM_T DB] | 8/15/2005 | JSL |
| EAST [USPAT;US- PGPUB;EPO;JPO;DERWENT;IBM_T DB] | 9/1/2005 | JSL |
| IEEE | 8/15/2005 | JSL |
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